

Design and Fabrication of a Radiation-Hard 500-MHz Digitizer Using Deep Submicron Technology

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Outline

- NLC Requirements
- ADC Design
- Plans

Beam Position Monitor Requirements at NLC

- NLC will collide 180-bunch trains of e^- and e^+ :
 - bunch spacing: 1.4 ns
 - alignment of individual bunches in a train: $< 1 \text{ } \mu\text{m}$
 - BPM determines bunch-to-bunch misalignment
 - ⇒ high bandwidth kickers bring the train into better alignment on next machine cycle
 - ⇒ multi-bunch BPM system with digitizers:
 - ★ 11-bit effective resolution
 - ★ 500 MHz bandwidth
 - ★ 2 G samples/s

Requirements of NLC Digitizers

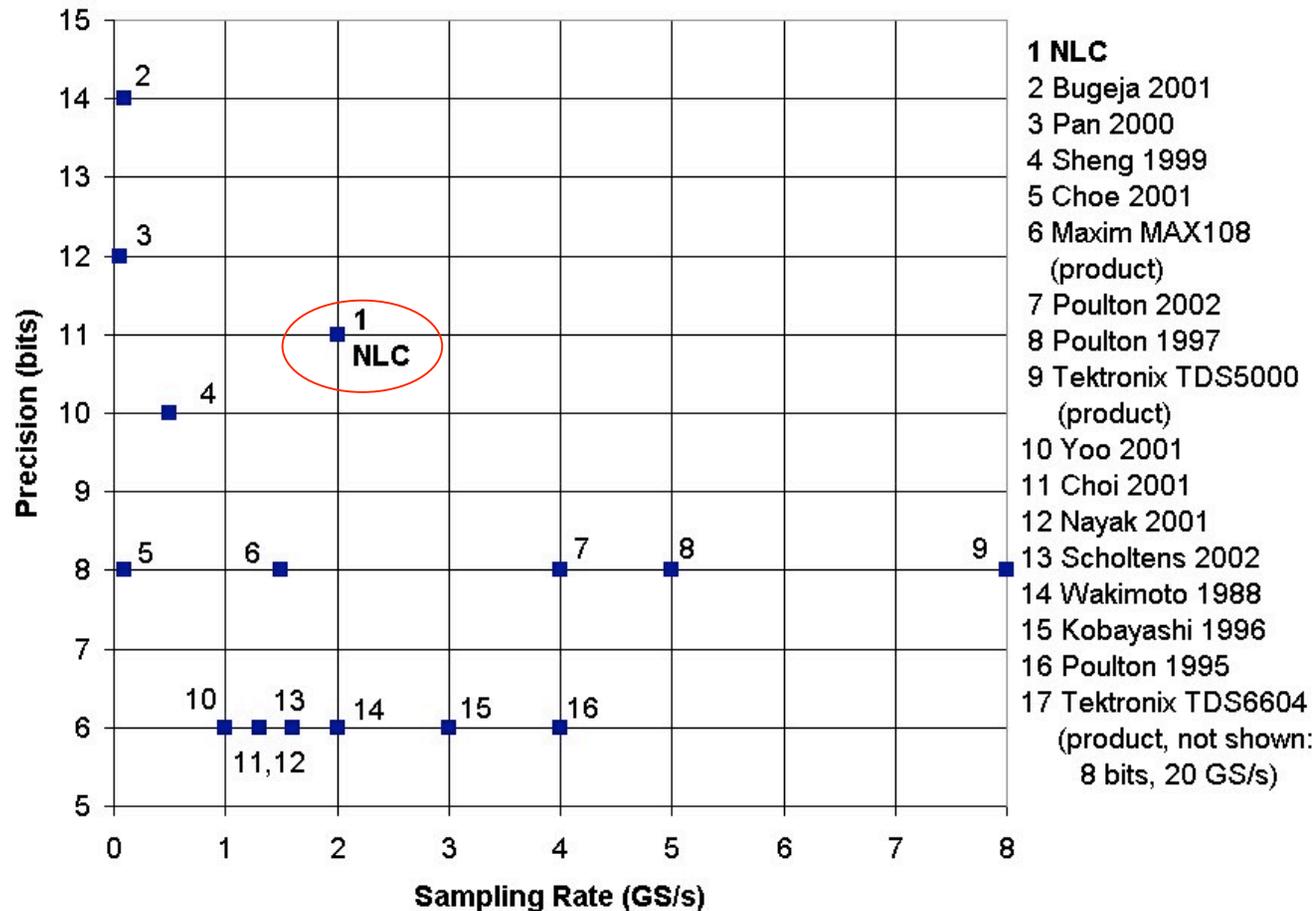
Function	Qty.	Resolution (eff. bits)	Bandwidth (MHz)	Comments
LLRF Control	13,000	11	100	Slightly beyond state-of-the-art
Structure BPM	22,000	8	5	Existing technology
“Qaud” BPM	10,000	11	12	Existing technology
Multi-bunch BPM	1,200	11	500	Well beyond state-of-the-art
Total	46,200			

- important to demonstrate feasibility of high speed/resolution digitizers
- ⇒ redesign of low level RF technology is needed without the digitizers

Proposal

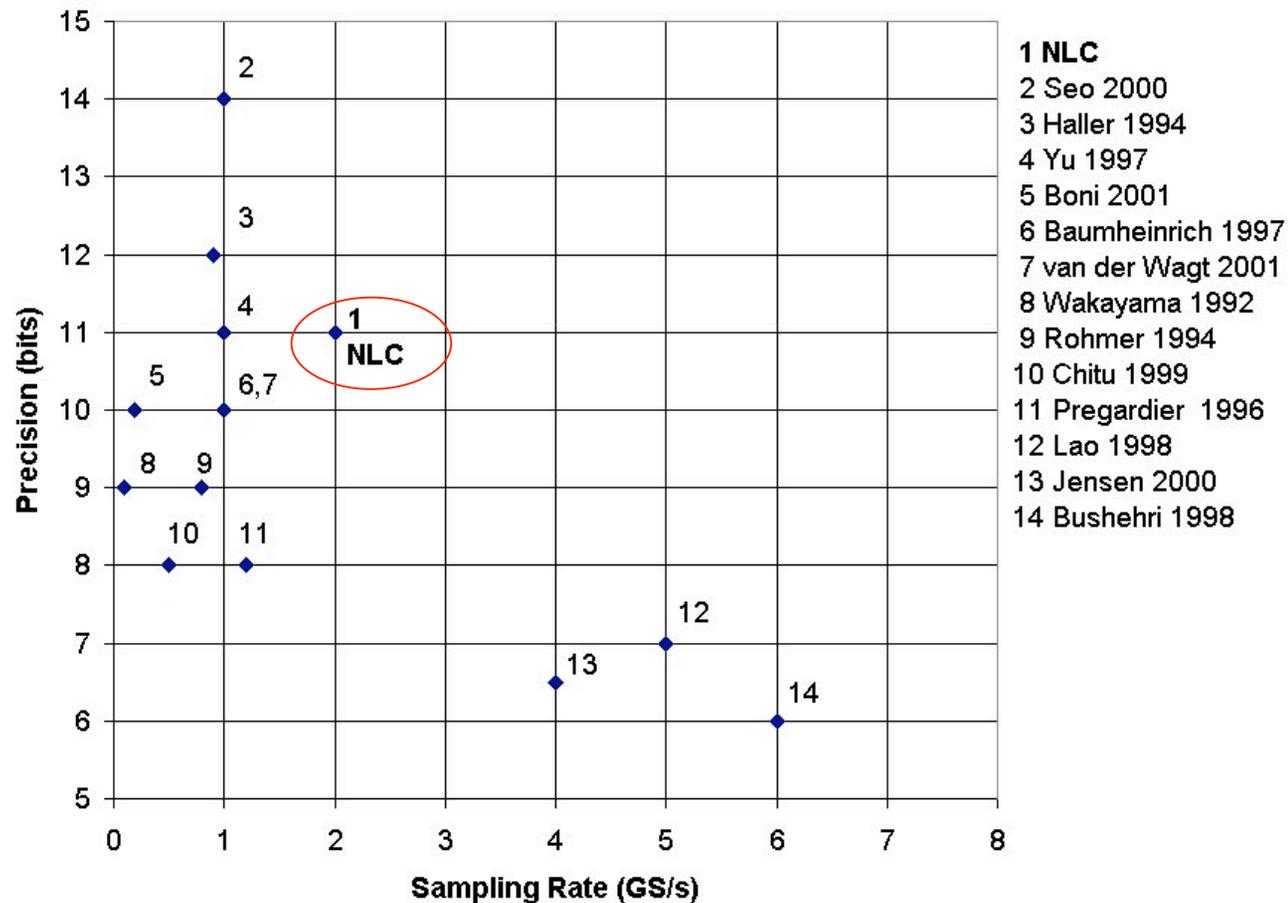
- design a digitizer chip using deep-submicron technology (0.25 μ m)
 - radiation hard: > 60 Mrad
 - ⇒ no need for costly shielding and long cables
 - ⇒ readily access to electronics for testing and maintenance
- extensive experience in chip design using Cadence
 - design radiation-hard chip for CLEO III, ATLAS, CMS
- why OSU is interested?
 - help to solve a challenging NLC problem
 - potential applications in HEP
- Holtkamp Committee ranking: 2 on scale of 1 to 4 (lowest)

Current State-of-the-Art in Digitizer



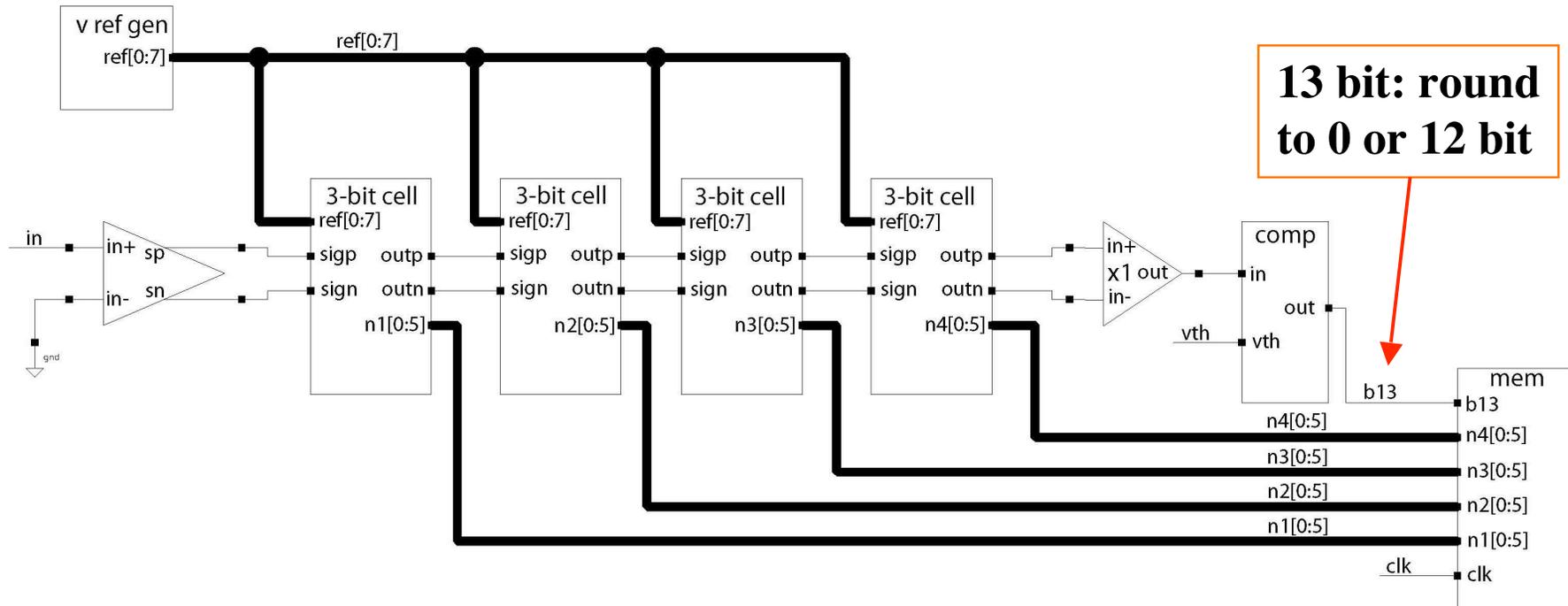
- NLC requirement is somewhat beyond state-of-the-art

Current State-of-the-Art in Sample/Hold



- NLC requirement is somewhat beyond state-of-the-art

12-bit Pipelined Digitizer



- input crudely digitized by 1st 3-bit cell
- ⇒ digitized value subtracted from input
- ⇒ difference is amplified by 8 and send to 2nd 3-bit cell...

Digitizer for Multi-bunch BPM

- most challenging digitizer: 11 bit, 2 G samples /s, 500 MHz bandwidth
- input: sequence of doublets at 1.4 ns batch spacing
 - characterize with one parameter: pulse height
 - minimum sampling: $1/1.4 \text{ ns} = 714 \text{ MHz}$
 - ⇒ interleaving 3 digitizers for redundancy
 - ⇒ 2 G samples/s

Precision

- submicron CMOS supply voltage: 2.5 V
 - ⇒ differential signal: ~ 3 V full swing
 - ⇒ LSB: $3 \text{ V}/2^{12} = 732 \text{ } \mu\text{V}$
 - ⇒ stability/accuracy of comparator thresholds, amplifier & S/H gains, charge injection:
 $366 \text{ } \mu\text{V} = 0.5 \text{ LSB} = 0.5/2^{12} = 0.01\%$

Error Control

- three types of errors in digitizer
 - offset: comparator thresholds, amplifiers, S/H
 - gain: amplifiers, S/H
 - ⇒ 72 calibration values for offset and gain errors to be stored into on-chip memory
 - dynamic: timing, amplifiers & S/H settling
 - ⇒ dynamic errors are controlled via careful simulation/design to ensure each circuit has sufficient bandwidth to settle in required time

Fabrication Process

- gain-bandwidth requirement:
 - assume 0.7 ns for sample and 0.7 ns for hold
 - settling to 0.5 LSB for 12-bit digitizer requires $9 \times 0.5/2^{12} \sim e^{-9}$
 - ⇒ $\tau = 0.7 \text{ ns}/9 = 171 \text{ ps}$
 - ⇒ gain x bandwidth = $8 \times 1/2 \times \tau = 16.4 \text{ GHz}$
 - ⇒ IBM process SiGe BiCMOS 6HP/6DM via MOSIS:
40 GHz NPN bipolar transistors

Plans

- require six prototypes over three years
- has been funded by DOE for design/simulation in first year
 - goal: has most circuit blocks ready
for prototyping by end of first year